

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2725	(first near5 polysilicon).clm.	US-PGPU B	OR	ON	2007/06/24 18:52
L2	2546	(second near5 polysilicon).clm.	US-PGPU B	OR	ON	2007/06/24 18:52
L3	610	1 and ((etch\$3 pattern\$3) near5 (first near5 polysilicon)).clm.	US-PGPU B	OR	ON	2007/06/24 18:56
L5	30	3 and ((thermal\$3 near8 oxid\$6) same (first near8 polysilicon)).clm.	US-PGPU B	OR	ON	2007/06/24 18:58
L6	28	2 and 5	US-PGPU B	OR	ON	2007/06/24 18:58

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S13	221	S12 and (thermal\$3 near5 (oxide oxidation oxidizing))	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:15
S14	17	(implant\$3 dop\$3) same nitrogen same front same polysilicon	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:54
S15	4	(implant\$3 dop\$3) and nitrogen and front and polysilicon	FPRS; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/09/30 13:25
S16	970	(implant\$3 dop\$3) same ("N.sub.2" nitrogen) same surface same polysilicon	US-PGPU B; USPAT; USOCR	OR	ON	2006/09/30 13:27
S17	196	(implant\$3 dop\$3) and ("N.sub.2" nitrogen) and surface and polysilicon	FPRS; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2006/09/30 13:27
S18	138645	(flash (non near3 volatile) eeprom eprom e2prom)	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:49
S19	20432	S18 and (float\$3 ner5 gate)	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:50
S20	8427	S19 and (control near5 gate)	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:15
S21	250	S20 and (thermal\$3 near5 (oxide oxidation oxidizing))	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:51

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S22	53	S21 and thickness	EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/20 12:51
S23	176	thermal same oxidation same polysilicon same thickness same side same (wall face) same surface	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:33
S24	497063	(flash (non near3 volatile) eeprom eprom e2prom)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:49
S25	121399	S24 and (float\$3 ner5 gate)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:50
S26	121399	S25 and (float\$3 ner5 gate)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:50
S27	9977	S26 and (thermal\$3 near5 (oxide oxidation oxidizing))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:51
S28	8996	S27 and thickness	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:52
S29	1956	S28 and ((thermal\$3 near5 (oxide oxidation oxidizing)) same (first near5 (silicon polysilicon)))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:56
S30	3	S29 and ((implant\$3 dop\$3) same nitrogen same front same polysilicon)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:54
S31	54	S29 and (thickness same oxide same (side sidewall) same (front face))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/20 12:57
S32	136	thermal near20 oxid\$6 near20 gate near20 thick near20 thin near20 oxide	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/22 22:09
S33	55	S32 and (float\$3 near8 gate)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/22 22:05

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S34	180	thermal same oxid\$6 same gate same thick same thin same oxide	FPRS; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/22 22:09
S35	2816	(438/257).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 14:33
S36	1034	S35 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:50
S37	1	10/761223	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:12
S38	1799	(438/258-260).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 14:49
S39	651	S38 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:33
S40	475	S39 not S36	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:42
S41	1	("5,017,979").PN.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 14:42
S42	1195	(438/261-263).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 14:50
S43	505	S42 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:50
S44	1509	S39 S36	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 14:50
S45	277	S43 not S44	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:10
S46	2816	(438/257).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 15:10

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S47	1034	S46 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:17
S48	1799	(438/258-260).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 15:10
S49	651	S48 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:51
S50	1195	(438/261-263).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 15:17
S51	505	S50 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:10
S52	1509	S49 S47	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:10
S53	277	S51 not S52	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:10
S54	1980	(438/263-267).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 15:17
S55	829	S54 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:18
S56	1786	S47 S49 S51	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:18
S57	317	S55 not S56	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:51
S58	2103	S47 S49 S51 S55	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 15:51
S59	1547	(257/314).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:13
S60	515	S59 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:13

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S61	379	S60 not S58	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57
S62	3932	(257/315-317).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 17:28
S63	1306	S62 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:13
S64	3514	S58 S59	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:13
S65	773	S63 not S64	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:14
S66	3932	(257/315-317).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S67	2816	(438/257).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S68	1034	S67 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:58
S69	1799	(438/258-260).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S70	651	S69 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57
S71	1195	(438/261-263).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S72	505	S71 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57
S73	1980	(438/263-267).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S74	829	S73 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57

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S75	2103	S68 S70 S72 S74	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:58
S76	1547	(257/314).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 16:57
S77	515	S76 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57
S78	379	S77 not S75	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:57
S79	1306	S66 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:28
S80	2482	S68 S70 S72 S74 S78	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:58
S81	773	S79 not S80	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 16:59
S82	2133	S80 and (thickness near8 (insulat\$3 dielectric oxide))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:29
S83	661	S81 and (thickness near8 (insulat\$3 dielectric oxide))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:00
S84	1601	(257/318-321).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2007/06/24 17:28
S85	532	S84 and (thermal near5 oxid\$3)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:28
S86	489	S85 and (thickness near8 (insulat\$3 dielectric oxide))	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:31
S87	2482	S80 S82	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:32
S88	293	S86 not S87	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:41

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S89	0	variable near8 thickness near8 inter near8 poly near8 dielectric	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:43
S90	499	variable near8 thickness near8 dielectric	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:47
S91	12	S90 and (float\$3 near5 gate)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:47
S92	30	S90 and (control near5 gate)	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:45
S93	7	S91 and S92	US-PGPU B; USPAT; USOCR	OR	ON	2007/06/24 17:45
S94	63	variable near8 thickness near8 dielectric	FPRS; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/24 17:47
S95	1	S94 and (float\$3 near5 gate)	FPRS; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/06/24 17:47